

Notice of References Cited	Application/Control No. 10/756,784		Applicant(s)/Patent Under Reexamination HUSLAK ET AL.	
	Examiner LISA HASHEM		Art Unit 2614	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0182425 A1	09-2003	Kurakake, Shoji	709/226
*	B	US-6,621,793 B2	09-2003	Widegren et al.	370/230.1
*	C	US-2004/0228363 A1	11-2004	Adamczyk et al.	370/468
*	D	US-2004/0252698 A1	12-2004	Anschutz et al.	370/395.21
*	E	US-2005/0021716 A1	01-2005	Adamczyk et al.	709/223
*	F	US-2005/0015493 A1	01-2005	Anschutz et al.	709/226
*	G	US-2005/0010638 A1	01-2005	Richardson et al.	709/204
*	H	US-2005/0015494 A1	01-2005	Adamczyk et al.	709/226
*	I	US-2005/0025136 A1	02-2005	Anschutz et al.	370/352
*	J	US-2005/0286535 A1	12-2005	Shrum et al.	370/395.21
*	K	US-7,106,718 B2	09-2006	Oyama et al.	370/340
*	L	US-7,382,785 B2	06-2008	Chen et al.	370/399
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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